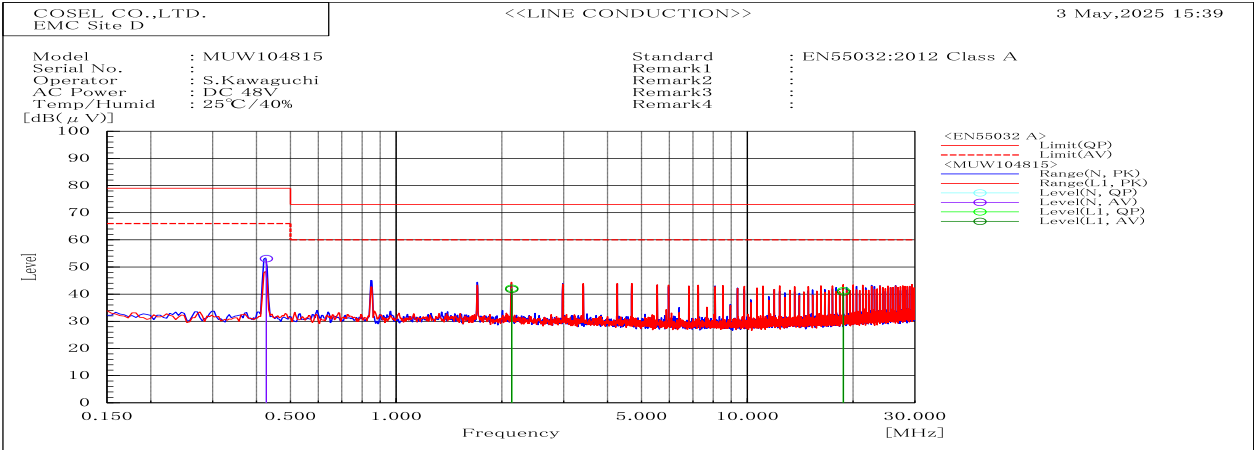
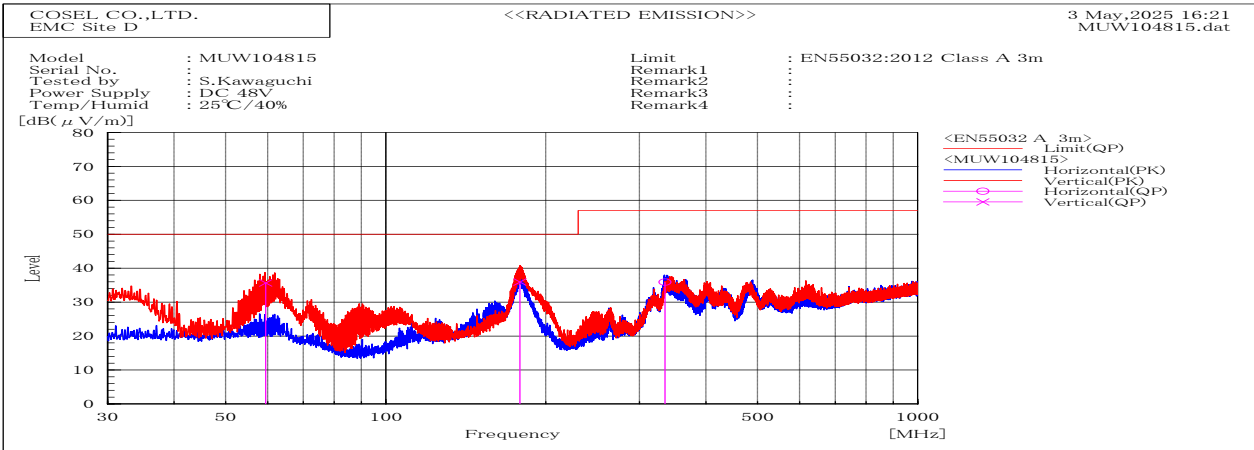


DATA SHEET		Date	03-May-25
Model	MUW104815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



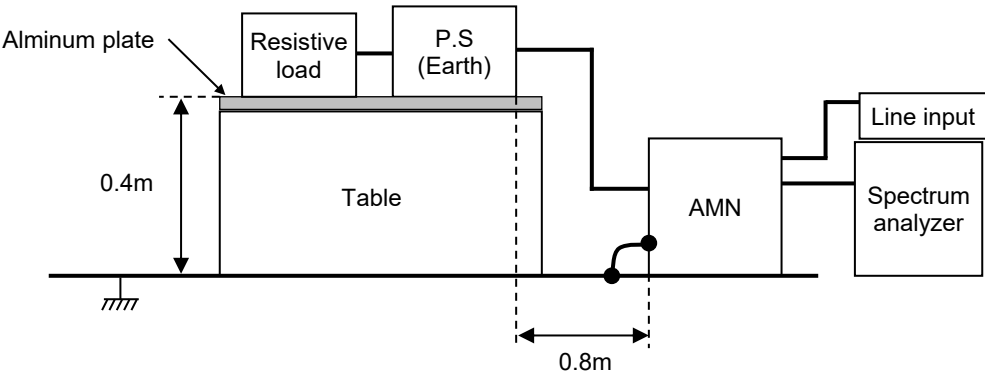
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
2.133	L1	42.2	41.8	73	60	30.8	18.2	Pass	
18.771	L1	41.3	40.8	73	60	31.7	19.2	Pass	
0.427	N	53.2	53.1	79	66	25.8	12.9	Pass	



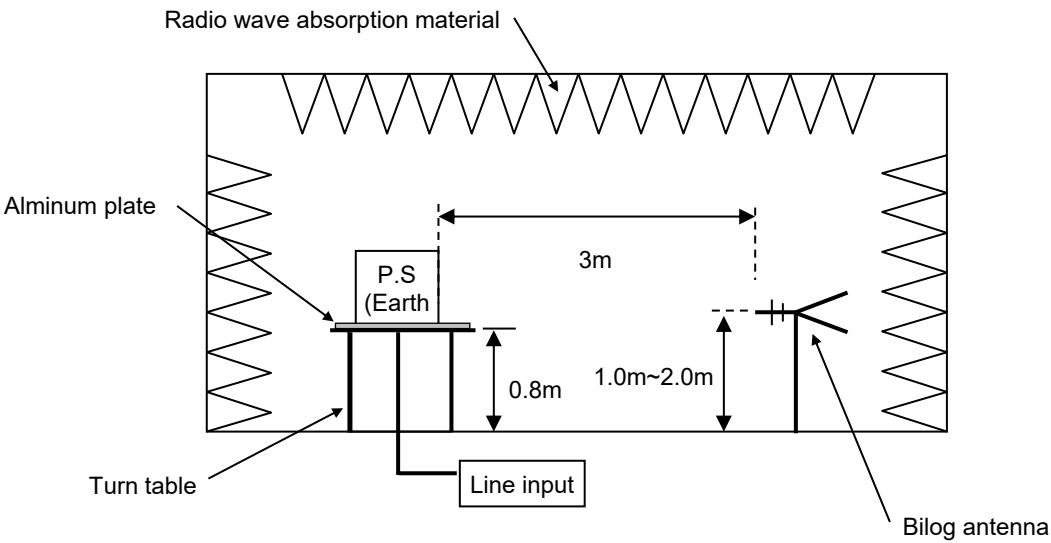
Frequency MHz	Polarization	Stability	Level dB(uV/m)		Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP						
178.789	V	Stable	35.9	50	14.1	Pass	100.3	349.9		
59.47	V	Stable	35.7	50	14.3	Pass	100.3	232.9		
334.975	H	Stable	35.9	57	21.1	Pass	100.3	238.6		

DATA SHEET		Date	03-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

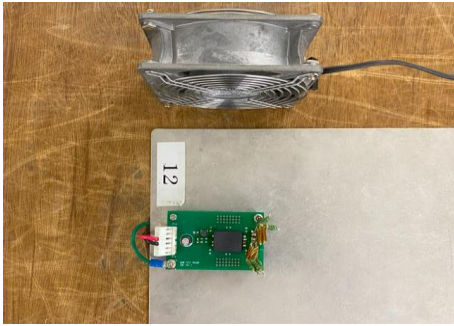
Test : EMI
Model Name: MUW10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

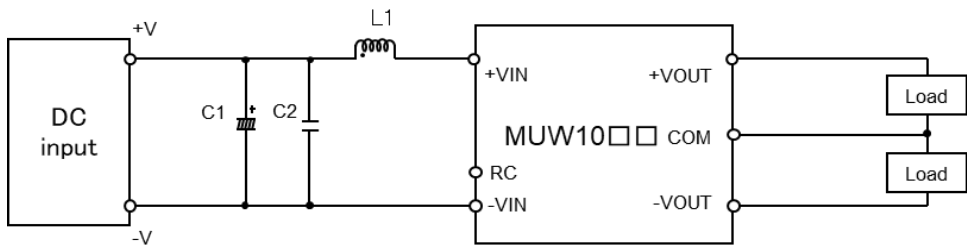


Fig.1 MUW10□□ Testing circuitry

- | | | | |
|------|----------|--------------------|---|
| C1 : | MUW1005□ | 25V 1500 μ F | Electric capacitor (LXZseries NIPPON CHEMI-CON) |
| | MUW1012□ | 50V 100 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW1024□ | — | — |
| | MUW1048□ | — | — |
| C2 : | MUW1005□ | 16V 22 μ F | Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING) |
| | MUW1012□ | 25V 10 μ F | Ceramic capacitor (CM316X7R106K25AT KYOCERA) |
| | MUW1024□ | 50V 4.7 μ F | Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING) |
| | MUW1048□ | 100V 2.2 μ F | Ceramic capacitor (C3216X7S2A225KT TDK) |
| L1 : | MUW1005□ | 5000mA 2.2 μ H | Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING) |
| | MUW1012□ | 3500mA 4.7 μ H | Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING) |
| | MUW1024□ | 1600mA 22 μ H | Inductor(LQH5BPN220M38 MURATA MANUFACTURING) |
| | MUW1048□ | 1100mA 47 μ H | Inductor(LQH5BPN470M38 MURATA MANUFACTURING) |